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Contents

v Conference Committee

OPTICAL TECHNOLOGY AND MEASUREMENT FOR INDUSTRIAL APPLICATIONS CONFERENCE 2025

13704 02 **Subwavelength beam shift at the reflection of orbital angular momentum-induced beam generated by vortex retarder** [13704-1]

13704 03 **Non-destructive spectral reflectance measurements of antireflection coating on optical lenses with small radius of curvature** [13704-2]

13704 04 **Design of a large aperture high-resolution fisheye lens for automotive surround-view systems** [13704-3]

13704 05 **Application of high-resolution large aperture wide-angle lenses in advanced automotive vision systems** [13704-4]

13704 06 **Surface detection based on autofluorescence signal for three-dimensional measurement** [13704-5]

13704 07 **Data acquisition method for dynamic resolution imaging of compressive sensing-based single-pixel camera** [13704-6]

13704 08 **Occlusion supporting augmented reality near-eye display** [13704-7]

13704 09 **Measurement technique for scattering characteristics of surface defects of optical components** [13704-12]

13704 0A **Confocal spectropolarimetric microscope based on channeled spectropolarimetry** [13704-13]

13704 0B **The influence of focus position on photonic nanojet formation for sub-micrometer scale pulsed laser ablation in water medium** [13704-14]

13704 0C **Laser measurement of high-speed displacement using intensity correlation between probe and phase-modulated reference signals** [13704-15]

13704 0D **Simultaneous image stacks collection with continuous rotating-compensator of imaging ellipsometers** [13704-16]

13704 0E **Performance verification test for the underwater laser Doppler velocimeter in deep-sea area** [13704-17]

13704 0F **Calibration method for broadband optical angle measurement** [13704-18]

13704 0G **Non-destructive inspection on the coatings of interior decoration with multispectral imaging module** [13704-19]

13704 0H **Research on image quality optimization and point cloud processing algorithms for micro-bump height measurement** [13704-21]

13704 0I **Chromatic confocal microscopy with galvanometer scanning and CNN-based deconvolution for precise full-field surface profilometry** [13704-22]

13704 0J **Addressing optical path maintenance need in infrared small target detection applications** [13704-23]

13704 0K **Development of a ramp-up photodetector for underwater laser scanner** [13704-24]

13704 0L **Towards miniaturization of single-pixel imaging systems: preliminary experimental demonstrations with fibers** [13704-25]

13704 0M **Study of the effects of confined water vapor in mesoporous silica on its mass transport analysis for thermal energy storage applications** [13704-26]

13704 0N **Snapshot channeled Mueller matrix spectropolarimetry** [13704-27]

13704 0O **Optical critical dimension metrology of HAR micro and sub-micro structures using AI-driven optical scatterometry for advanced semiconductor packaging** [13704-28]

13704 0P **On-line hydrogen quality control for fuel stations using Raman spectroscopy** [13704-29]

13704 0Q **Comparative spectral analysis of tapered optical fiber Mach–Zehnder interferometer as chloride ion concentration sensor** [13704-30]

13704 0R **Structural chirality and optical properties of Scarabaeidae beetles** [13704-31]

13704 0S **Classification of microplastics in living organism using color polarization camera** [13704-34]

13704 0T **Application of fisheye lenses in sky polarization measurement and its compensation method** [13704-35]

13704 0U **Snapshot partial Mueller matrix imaging using spatial optical phase modulator** [13704-36]